

### FINAL PRODUCT/PROCESS CHANGE NOTIFICATION

Generic Copy

#### 28-Jul-2008

SUBJECT: ON Semiconductor Final Product/Process Change Notification #16132

**TITLE: Final Notification for Changes in Device Specifications** 

PROPOSED FIRST SHIP DATE: 28-Oct-2008

AFFECTED CHANGE CATEGORY(S): High Frequency Products

AFFECTED PRODUCT DIVISION(S): Analog Standard Components

#### FOR ANY QUESTIONS CONCERNING THIS NOTIFICATION:

Contact your local ON Semiconductor Sales Office or Clarence Rebello < C.Rebello@onsemi.com >

SAMPLES: Contact your local ON Semiconductor Sales Office

#### **ADDITIONAL RELIABILITY DATA:** Available

Contact your local ON Semiconductor Sales Office or Matt Kas <Matt.Kas@onsemi.com>

### **NOTIFICATION TYPE:**

Final Product/Process Change Notification (FPCN)

Final change notification sent to customers. FPCNs are issued at least 90 days prior to implementation of the change.

ON Semiconductor will consider this change approved unless specific conditions of acceptance are provided in writing within 30 days of receipt of this notice. To do so, contact your local ON Semiconductor Sales Office.

## **DESCRIPTION AND PURPOSE:**

ON Semi is revising the MC10EP16VA and MC100EP16VA, MC100EP16VB and MC100EP16VC Product Family specifications after re-characterization based on improved Test Equipment and Measurements. There is no change to the Wafer and / or the Assembly Process. The effective date of this change will be 90 days from the issuance of this PCN for the devices listed. Reliability will continue to meet or exceed ON Semiconductor standards. ON Semiconductor recommends that customers evaluate units in each associated application to ensure there are no unexpected electrical incompatibilities exist.

Specification Changes are as Follows:

MC10EP16VA:

Change IEE Upper Limit at -40C to 36 (was 31) mA at -40C.

## MC100EP16VA:

Change IEE Limits at -40C to 22 to 38 (was 20 to 36) mA; at 25C to 24 to 40 (was 22 to 38) mA; at +85C to 26 to 42 (was 24 to 40) mA.

Change VOL NECL Limits at All Temperatures to -1995 to -1745 (was -1945 to -1695) mV.

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#### MC100EP16VB:

Change IEE Limits at -40C to 27 to 47 (was 25 to 45) mA.

Change VOH NECL Limits at All Temperatures to -1145 to -895 (was -1175 to -925) mV.

Change VBB NECL Limits at All Temperatures to -1525 to -1325 (was -1570 to -1340) mV.

# MC100EP16VC:

Change IEE Limits at -40C to 27 to 47 (was 25 to 45) mA; at 25C to 32 to 52 (was 30 to 50) mA; at +85C to 34 to 54 (was 32 to 52) mA.

Change VOH NECL Limits at All Temperatures to -1145 to -895 (was -1175 to -925) mV.

Change VBB NECL Limits at All Temperatures to -1525 to -1325 (was -1570 to -1340) mV.

## **RELIABILITY DATA SUMMARY:**

Reliability Test Results: Not Applicapable since this is a Specification Change.

**ELECTRICAL CHARACTERISTIC SUMMARY:** Available upon Request In the course of reviewing the electrical data, it has been determined that all Device parameters will meet all Data Book specifications.

#### CHANGED PART IDENTIFICATION:

Changes do not affect Date Code.

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# ON Semiconductor

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# AFFECTED DEVICE LIST

MC10EP16VAD

MC10EP16VADG

MC10EP16VADR2

MC10EP16VADR2G

MC10EP16VADT

MC10EP16VADTG

MC10EP16VADTR2

MC10EP16VADTR2G

MC10EP16VAMNR4G

MCW100EP16VA

MC100EP16VAD

MC100EP16VADG

MC100EP16VADR2

MC100EP16VADR2G

MC100EP16VADT

MC100EP16VADTG

MC100EP16VADTR2

MC100EP16VADTR2G

MC100EP16VAMNR4G

MC100EP16VBD

MC100EP16VBDG

MC100EP16VBDR2

MC100EP16VBDR2G

MC100EP16VBDT

MC100EP16VBDTG

MC100EP16VBDTR2

MC100EP16VBDTR2G

MC100EP16VCD

MC100EP16VCDG

MC100EP16VCDR2

MC100EP16VCDR2G

MC100EP16VCDT

MC100EP16VCDTG

MC100EP16VCDTR2

MC100EP16VCDTR2G

MC100EP16VCMNR4G

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